

Specification for Approval

Date: 2025/04/01

Customer: **Blume**

TAI-TECH P/N: **SWI1008UF-5R6G**

CUSTOMER P/N:

DESCRIPTION:

QUANTITY: pcs

REMARK:

Customer Approval Feedback

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High Frequency Winding Type Chip Inductor [SWI1008UF-5R6G](#)**ECN HISTORY LIST**

REV	DATE	DESCRIPTION	APPROVED	CHECKED	DRAWN
1.0	25/04/01	新 發 行	鍾百烜	徐鋒強	林靜婷
備 註					

High Frequency Winding Type Chip Inductor

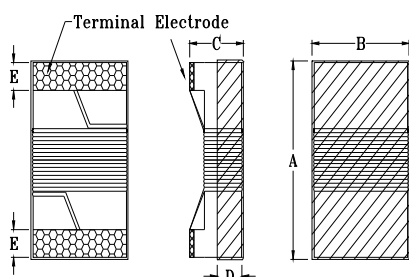
SWI1008UF-5R6G

1. Features

1. Ceramic core wire wound construction.
2. No batch to batch variations in inductance.
3. High Reliability due to ceramic wire wound construction.
4. High frequency application.
5. Small footprint as well as low profile.
6. 100% Lead(Pb) & Halogen-Free and RoHS compliant.
7. Operating temperature -40~+125°C (Including self - temperature rise).



2. Dimensions



Size	A(mm)	B(mm)	C(mm)	D(mm)	E(mm)
SWI1008	2.92 max.	2.79 max.	2.20 max.	1.20 ref.	0.55±0.10

Unit: mm

3. Part Numbering

SWI	1008	U	F	-	5R6	G
A	B	C	D		E	F

A: Series

B: Dimension

LxW

C: Material

D: Lead Free Code

E: Inductance

5R6=5600nH

F: Inductance Tolerance

G=±2%

4. Specification

Part Number	Inductance (nH)	Tolerance	Test Frequency (Hz)	Q min.	Test Frequency (MHz)	Rated Current (mA) max.	DCR (Ω) max.	SRF (MHz) min.
SWI1008UF-5R6G	5600	G	0.1V/7.9M	18	7.9	200	4.00	25

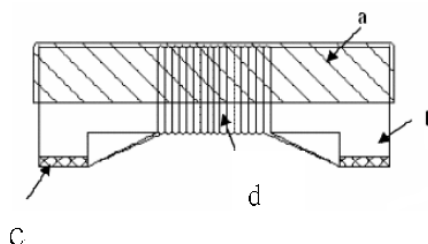
Note:

- All test data referenced to 25°C ambient.
- DC current at 25°C that causes the specified inductance drop from its value without current.
- Current that causes the specified temperature rise from 25°C ambient.

This information is for reference only and does not represent absolute maximum ratings.

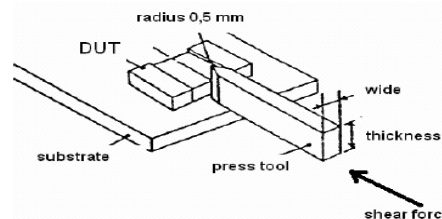
5. Materials

No.	Description	Specification
a.	Upper Plate	UV Glue
b.	Core	Ceramics Core
c.	Termination	Ag/Ni/Sn
d.	Wire	Enameled Copper Wire



6. Reliability and Test Condition

Item	Performance	Test Condition
Operating temperature	-40~+125℃ (Including self - temperature rise)	
Storage temperature	-40~+125℃ (on board)	
Electrical Performance Test		
Inductance	Refer to standard electrical characteristic list	Keysight E4991B, Keysight 4980AL
Q		Agilent-4287, Agilent-4285
SRF		Keysight E4991B
DCR		Agilent-34420A Agilent-4338B
Rated Current		Applied the current to coils, the inductance change shall be less than 20% to initial value.
Reliability Test		
Life Test	Appearance : No damage. Inductance : within±10% of initial value Q : Shall not exceed the specification value. DCR : within±15% of initial value and shall not exceed the specification value	Preconditioning: Run through reflow for 3 times. (IPC/JEDECJ-STD-020F Classification Reflow Profiles) Temperature : 125±2℃ Applied current : rated current Duration : 1000±12hrs Measured at room temperature after placing for 24 hrs.
Load Humidity		Preconditioning: Run through reflow for 3 times. (IPC/JEDECJ-STD-020F Classification Reflow Profiles) Humidity : 85±3% RH Temperature : 85℃±2℃ Duration : 1000hrs Min. Bead : with 100% rated current Inductance : with 10% rated current Measured at room temperature after placing for 24 hrs.
Moisture Resistance		Preconditioning: Run through reflow for 3 times. (IPC/JEDECJ-STD-020F Classification Reflow Profiles) 1. Baked at 50℃ for 25hrs, measured at room temperature after placing for 4 hrs. 2. Raise temperature to 65±2℃ 90-100%RH in 2.5hrs, and keep 3 hours, cool down to 25℃ in 2.5hrs. 3. Raise temperature to 65±2℃ 90-100%RH in 2.5hrs, and keep 3 hours, cool down to 25℃ in 2.5hrs, keep at 25℃ for 2hrs then keep at -10℃ for 3hrs. 4. Keep at 25℃ 80-100%RH for 15min and vibrate at the frequency of 10 to 55 Hz to 10 Hz, measured at room temperature after placing for 1~2 hrs.
Thermal Shock		Preconditioning: Run through reflow for 3 times. (IPC/JEDECJ-STD-020F Classification Reflow Profiles) Condition for 1 cycle Step1 : -40±2℃ 30±5min Step2 : 125±2℃ ≤0.5min Step3 : 125±2℃ 30±5min Number of cycles : 500 Measured at room temperature after placing for 24 hrs.
Vibration		Preconditioning: Run through reflow for 3 times. (IPC/JEDECJ-STD-020F Classification Reflow Profiles) Oscillation Frequency : 10Hz~2kHz~10Hz for 20 minutes Equipment : Vibration checker Total Amplitude : 10g Testing Time : 12 hours (20 minutes, 12 cycles each of 3 orientations)

Item	Performance	Test Condition														
Bending	Appearance : No damage. Inductance : within±10% of initial value Q : Shall not exceed the specification value. DCR : within±15% of initial value and shall not exceed the specification value	Shall be mounted on a FR4 substrate of the following dimensions: >=0805 inch(2012mm):40x100x1.2mm <0805 inch(2012mm):40x100x0.8mm Bending depth: >=0805 inch(2012mm):1.2mm <0805 inch(2012mm):0.8mm duration of 10 sec.														
Shock		<table><tr><th>Type</th><th>Peak value (g's)</th><th>Normal duration (D) (ms)</th><th>Wave form</th><th>Velocity change (Vi)ft/sec</th></tr><tr><td>SMD</td><td>50</td><td>11</td><td>Half-sine</td><td>11.3</td></tr><tr><td>Lead</td><td>50</td><td>11</td><td>Half-sine</td><td>11.3</td></tr></table> 3 shocks in each direction along 3 perpendicular axes. (18 shocks)	Type	Peak value (g's)	Normal duration (D) (ms)	Wave form	Velocity change (Vi)ft/sec	SMD	50	11	Half-sine	11.3	Lead	50	11	Half-sine
Type	Peak value (g's)	Normal duration (D) (ms)	Wave form	Velocity change (Vi)ft/sec												
SMD	50	11	Half-sine	11.3												
Lead	50	11	Half-sine	11.3												
Solderability	More than 95% of the terminal electrode should be covered with solder	a. Method B, 4hrs @155°C dry heat @235°C±5°C Testing Time :5 +0/-0.5 seconds b. Method D category 3. (8hours ± 15 min)@ 260°C±5°C Testing Time :30 +0/-0.5 seconds														
Resistance to Soldering Heat		Depth: completely cover the termination <table><tr><th>Temperature(°C)</th><th>Time(s)</th><th>Temperature ramp/immersion and emersion rate</th><th>Number of heat cycles</th></tr><tr><td>260 ±5 (solder temp)</td><td>10 ±1</td><td>25mm/s ±6 mm/s</td><td>1</td></tr></table>	Temperature(°C)	Time(s)	Temperature ramp/immersion and emersion rate	Number of heat cycles	260 ±5 (solder temp)	10 ±1	25mm/s ±6 mm/s	1						
Temperature(°C)	Time(s)	Temperature ramp/immersion and emersion rate	Number of heat cycles													
260 ±5 (solder temp)	10 ±1	25mm/s ±6 mm/s	1													
Terminal Strength	Appearance : No damage. Inductance : within±10% of initial value Q : Shall not exceed the specification value. DCR : within±15% of initial value and shall not exceed the specification value	Preconditioning: Run through reflow for 3 times. (IPC/JEDEC J-STD-020F Classification Reflow Profiles) With the component mounted on a PCB with the device to be tested, apply a force (>0805:1kg, <=0805:0.5kg) to the side of a device being tested. This force shall be applied for 60 +1 seconds. Also the force shall be applied gradually as not to apply a shock to the component being tested. 														

Note:

The main function of UV coating is for the pick and place of SMT machine.

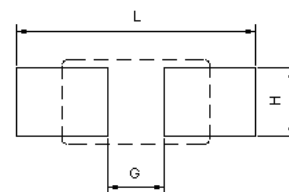
For UV coating on the top side. In rare cases, some very small cracks may appear on the coating surface after being exposed after many times of IR reflow, long times of high and low temperature, high humidity and temperature cycles.

Small cracks on UV coating will not affect functions of this product.

7. Soldering and Mounting

7-1. Recommended PC Board Pattern

Chip size						Land Patterns For Reflow Soldering			
Series	Type	A(mm)	B(mm)	C(mm)	D(mm)	E(mm)	L(mm)	G(mm)	H(mm)
SWI	1008	2.92max	2.79max	2.20max	1.20 ref	0.55±0.1	3.31	1.526	2.54



7-2. Soldering

Mildly activated rosin fluxes are preferred. TAI-TECH terminations are suitable for re-flow soldering systems. If hand soldering cannot be avoided, the preferred technique is the utilization of hot air soldering tools.

7-2.1 Soldering Reflow:

Recommended temperature profiles for lead free re-flow soldering in Figure 1. Table 1.1&1.2 (J-STD-020F)

7-2.2 Soldering Iron:

Products attachment with a soldering iron is discouraged due to the inherent process control limitations. In the event that a soldering iron must be employed the following precautions are recommended. (Figure 2.)

- Preheat circuit and products to 150°C
- Never contact the ceramic with the iron tip
- Use a 20 watt soldering iron with tip diameter of 1.0mm
- 350°C tip temperature (max)
- 1.0mm tip diameter (max)
- Limit soldering time to 4~5sec.

Fig.1 Soldering Reflow

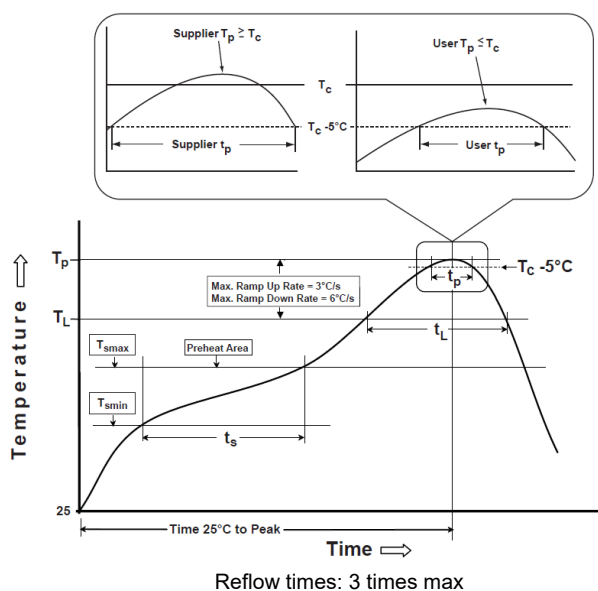


Fig.2 Iron soldering temperature profiles

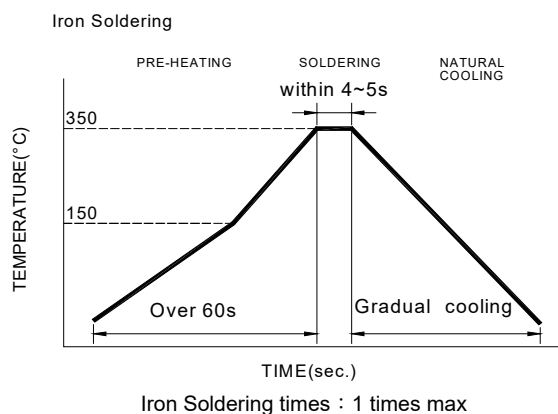


Table (1.1): Reflow Profiles

Profile Type:	Pb-Free Assembly
Preheat -Temperature Min(T_{smin}) -Temperature Max(T_{smax}) -Time(t_s)from(T_{smin} to T_{smax})	150°C 200°C 60-120seconds
Ramp-up rate(T_L to T_p)	3°C/second max.
Liquidus temperature(T_L) Time(t_L)maintained above T_L	217°C 60-150 seconds
Classification temperature(T_c)	See Table (1.2)
Time(t_p) at $T_c - 5^\circ\text{C}$ (T_p should be equal to or less than T_c .)	< 30 seconds
Ramp-down rate(T_p to T_L)	6°C/second max.
Time 25°C to peak temperature	8 minutes max.

T_p : maximum peak package body temperature, T_c : the classification temperature.

For user (customer) T_p should be equal to or less than T_c .

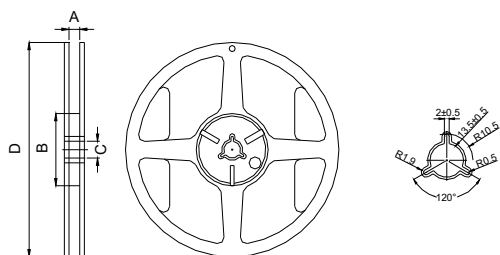
Table (1.2) Package Thickness/Volume and Classification Temperature (T_c)

	Package Thickness	Volume mm ³ <350	Volume mm ³ 350-2000	Volume mm ³ >2000
PB-Free Assembly	<1.6mm	260°C	260°C	260°C
	1.6-2.5mm	260°C	250°C	245°C
	≥2.5mm	250°C	245°C	245°C

Reflow is referred to standard IPC/JEDEC J-STD-020F

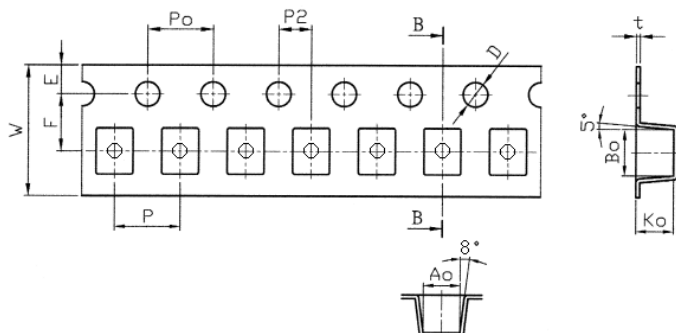
8. Packaging Information

8-1. Reel Dimension



Type	A(mm)	B(mm)	C(mm)	D(mm)
7"x8mm	8.4±0.5.0	60.0±2.0	13.5±0.5	178.0±2.0

8-2.1 Tape Dimension / 8mm

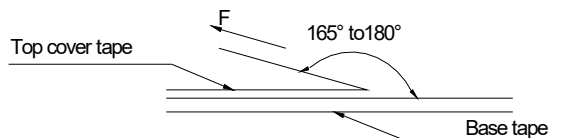


Series	W(mm)	P(mm)	E(mm)	F(mm)	P2(mm)	D(mm)	P0(mm)	A0(mm)	B0(mm)	K0(mm)	t(mm)
SW1008	8.00±0.10	4.00±0.10	1.75±0.10	3.50±0.05	2.00±0.05	1.50+0.10/-0.00	4.00±0.10	2.61±0.10	2.93±0.10	2.25±0.10	0.26±0.05

8-3. Packaging Quantity

Chip size	1008
Reel	2000
Reel Size	7"x8mm

8-4. Tearing Off Force



The force for tearing off cover tape is 15 to 80 grams in the arrow direction under the following conditions.

Room Temp. (°C)	Room Humidity (%)	Room atm (hPa)	Tearing Speed mm/min
5~35	45~85	860~1060	300

Application Notice

• Storage Conditions(component level)

To maintain the solderability of terminal electrodes:

1. TAI-TECH products meet IPC/JEDEC J-STD-020F standard-MSL, level 1.
2. Temperature and humidity conditions: Less than 40°C and 60% RH.
3. Recommended products should be used within 12 months from the time of delivery.
4. The packaging material should be kept where no chlorine or sulfur exists in the air.

• Transportation

1. Products should be handled with care to avoid damage or contamination from perspiration and skin oils.
2. The use of tweezers or vacuum pick up is strongly recommended for individual components.
3. Bulk handling should ensure that abrasion and mechanical shock are minimized.

測試報告

Test Report

號碼(No.): ETR25303011

日期(Date): 21-Mar-2025

頁數(Page): 1 of 11

西北臺慶科技股份有限公司 (TAI-TECH ADVANCED ELECTRONICS CO., LTD.)

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臺北市信義區信義路5段5號3樓E06室 (ROOM E06, 3RD FLOOR, NO.5, SECTION 5, XINYI ROAD, XINYI DISTRICT, TAIPEI CITY, TAIWAN)

以下測試樣品係由申請廠商所提供及確認 (The following sample(s) was/were submitted and identified by the applicant as) :

樣品名稱(Sample Name) : CERAMIC SERIES
樣品型號(Style/Item No.) : SWI(SWC) · SWC_I SERIES

收件日(Sample Receiving Date) : 13-Mar-2025
測試期間(Testing Period) : 13-Mar-2025 to 21-Mar-2025

測試需求(Test Requested) : 依據客戶要求進行測試·測試項目請參閱測試結果表格。(Testing item(s) is/are specified by client. Please refer to result table for testing item(s).)

測試結果(Test Results) : 請參閱下一頁 (Please refer to following pages.)


Troy Chang / Department Manager
Signed for and on behalf of
SGS TAIWAN LTD.
Chemical Laboratory - Taipei



PIN CODE: 68D7CB79

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測試部位敘述 (Test Part Description)

No.1 : 整體混測 (MIXED ALL PARTS)

測試結果 (Test Results)

測試項目 (Test Items)	測試方法 (Method)	單位 (Unit)	MDL	結果 (Result)
				No.1
鎘 (Cd) (Cadmium (Cd))	參考IEC 62321-5: 2013, 以感應耦合電漿發射光譜儀分析。(With reference to IEC 62321-5: 2013, analysis was performed by ICP-OES.)	mg/kg	2	n.d.
鉛 (Pb) (Lead (Pb))		mg/kg	2	n.d.
汞 (Hg) (Mercury (Hg))	參考IEC 62321-4: 2013+ AMD1: 2017, 以感應耦合電漿發射光譜儀分析。(With reference to IEC 62321-4: 2013+ AMD1: 2017, analysis was performed by ICP-OES.)	mg/kg	2	n.d.
六價鉻 Cr(VI) (Hexavalent Chromium Cr(VI))	參考IEC 62321-7-2: 2017, 以紫外光-可見光分光光度計分析。(With reference to IEC 62321-7-2: 2017, analysis was performed by UV-VIS.)	mg/kg	8	n.d.
一溴聯苯 (Monobromobiphenyl)	參考IEC 62321-6: 2015, 以氣相層析儀/質譜儀分析。(With reference to IEC 62321-6: 2015, analysis was performed by GC/MS.)	mg/kg	5	n.d.
二溴聯苯 (Dibromobiphenyl)		mg/kg	5	n.d.
三溴聯苯 (Tribromobiphenyl)		mg/kg	5	n.d.
四溴聯苯 (Tetrabromobiphenyl)		mg/kg	5	n.d.
五溴聯苯 (Pentabromobiphenyl)		mg/kg	5	n.d.
六溴聯苯 (Hexabromobiphenyl)		mg/kg	5	n.d.
七溴聯苯 (Heptabromobiphenyl)		mg/kg	5	n.d.
八溴聯苯 (Octabromobiphenyl)		mg/kg	5	n.d.
九溴聯苯 (Nonabromobiphenyl)		mg/kg	5	n.d.
十溴聯苯 (Decabromobiphenyl)		mg/kg	5	n.d.
多溴聯苯總和 (Sum of PBBs)		mg/kg	-	n.d.

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測試項目 (Test Items)	測試方法 (Method)	單位 (Unit)	MDL	結果 (Result)
				No.1
一溴聯苯醚 (Monobromodiphenyl ether)	參考IEC 62321-6: 2015 · 以氣相層析儀/質譜儀分析。(With reference to IEC 62321-6: 2015, analysis was performed by GC/MS.)	mg/kg	5	n.d.
二溴聯苯醚 (Dibromodiphenyl ether)		mg/kg	5	n.d.
三溴聯苯醚 (Tribromodiphenyl ether)		mg/kg	5	n.d.
四溴聯苯醚 (Tetrabromodiphenyl ether)		mg/kg	5	n.d.
五溴聯苯醚 (Pentabromodiphenyl ether)		mg/kg	5	n.d.
六溴聯苯醚 (Hexabromodiphenyl ether)		mg/kg	5	n.d.
七溴聯苯醚 (Heptabromodiphenyl ether)		mg/kg	5	n.d.
八溴聯苯醚 (Octabromodiphenyl ether)		mg/kg	5	n.d.
九溴聯苯醚 (Nonabromodiphenyl ether)		mg/kg	5	n.d.
十溴聯苯醚 (Decabromodiphenyl ether)		mg/kg	5	n.d.
多溴聯苯醚總和 (Sum of PBDEs)		mg/kg	-	n.d.
鄰苯二甲酸丁苯甲酯 (BBP) (Butyl benzyl phthalate (BBP))	參考IEC 62321-8: 2017 · 以氣相層析儀/質譜儀分析。(With reference to IEC 62321-8: 2017, analysis was performed by GC/MS.)	mg/kg	50	n.d.
鄰苯二甲酸二丁酯 (DBP) (Dibutyl phthalate (DBP))		mg/kg	50	n.d.
鄰苯二甲酸二(2-乙基己基)酯 (DEHP) (Di-(2-ethylhexyl) phthalate (DEHP))		mg/kg	50	n.d.
鄰苯二甲酸二異丁酯 (DIBP) (Diisobutyl phthalate (DIBP))		mg/kg	50	n.d.
鄰苯二甲酸二異癸酯 (DIDP) (Diisodecyl phthalate (DIDP)) (CAS No.: 26761-40-0, 68515-49-1)		mg/kg	50	n.d.

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測試項目 (Test Items)	測試方法 (Method)	單位 (Unit)	MDL	結果 (Result)
				No.1
鄰苯二甲酸二異壬酯 (DINP) (Diisononyl phthalate (DINP)) (CAS No.: 28553-12-0, 68515-48-0)	參考IEC 62321-8: 2017 · 以氣相層析儀/質譜儀分析。(With reference to IEC 62321-8: 2017, analysis was performed by GC/MS.)	mg/kg	50	n.d.
鄰苯二甲酸二正辛酯 (DNOP) (Di-n-octyl phthalate (DNOP)) (CAS No.: 117-84-0)		mg/kg	50	n.d.
鄰苯二甲酸二正戊酯 (DNPP) (Di-n-pentyl phthalate (DNPP)) (CAS No.: 131-18-0)		mg/kg	50	n.d.
鄰苯二甲酸二正己酯 (DNHP) (Di-n-hexyl phthalate (DNHP)) (CAS No.: 84-75-3)		mg/kg	50	n.d.
六溴環十二烷及所有主要被辨別出的異構物(HBCDD) (α- HBCDD, β- HBCDD, γ- HBCDD) (Hexabromocyclododecane (HBCDD) and all major diastereoisomers identified (α- HBCDD, β- HBCDD, γ- HBCDD)) (CAS No.: 25637-99-4, 3194-55-6 (134237-51-7, 134237-50-6, 134237-52-8))	參考IEC 62321-9: 2021 · 以氣相層析儀/質譜儀分析。(With reference to IEC 62321-9: 2021, analysis was performed by GC/MS.)	mg/kg	20	n.d.
氟 (F) (Fluorine (F)) (CAS No.: 14762-94-8)	參考BS EN 14582: 2016 · 以離子層析儀分析。(With reference to BS EN 14582: 2016, analysis was performed by IC.)	mg/kg	50	n.d.
氯 (Cl) (Chlorine (Cl)) (CAS No.: 22537-15-1)		mg/kg	50	n.d.
溴 (Br) (Bromine (Br)) (CAS No.: 10097-32-2)		mg/kg	50	n.d.
碘 (I) (Iodine (I)) (CAS No.: 14362-44-8)		mg/kg	50	n.d.

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備註(Note) :

1. mg/kg = ppm ; 0.1wt% = 0.1% = 1000ppm
2. MDL = Method Detection Limit (方法偵測極限值)
3. n.d. = Not Detected (未檢出) ; 小於MDL / Less than MDL
4. "-" = Not Regulated (無規格值)
5. 樣品的測試是基於申請人要求混合測試，報告中的混合測試結果不代表其中個別單一材質的含量。
The sample(s) was/were analyzed on behalf of the applicant as mixing sample in one testing. The above result(s) was/were only given as the informality value.

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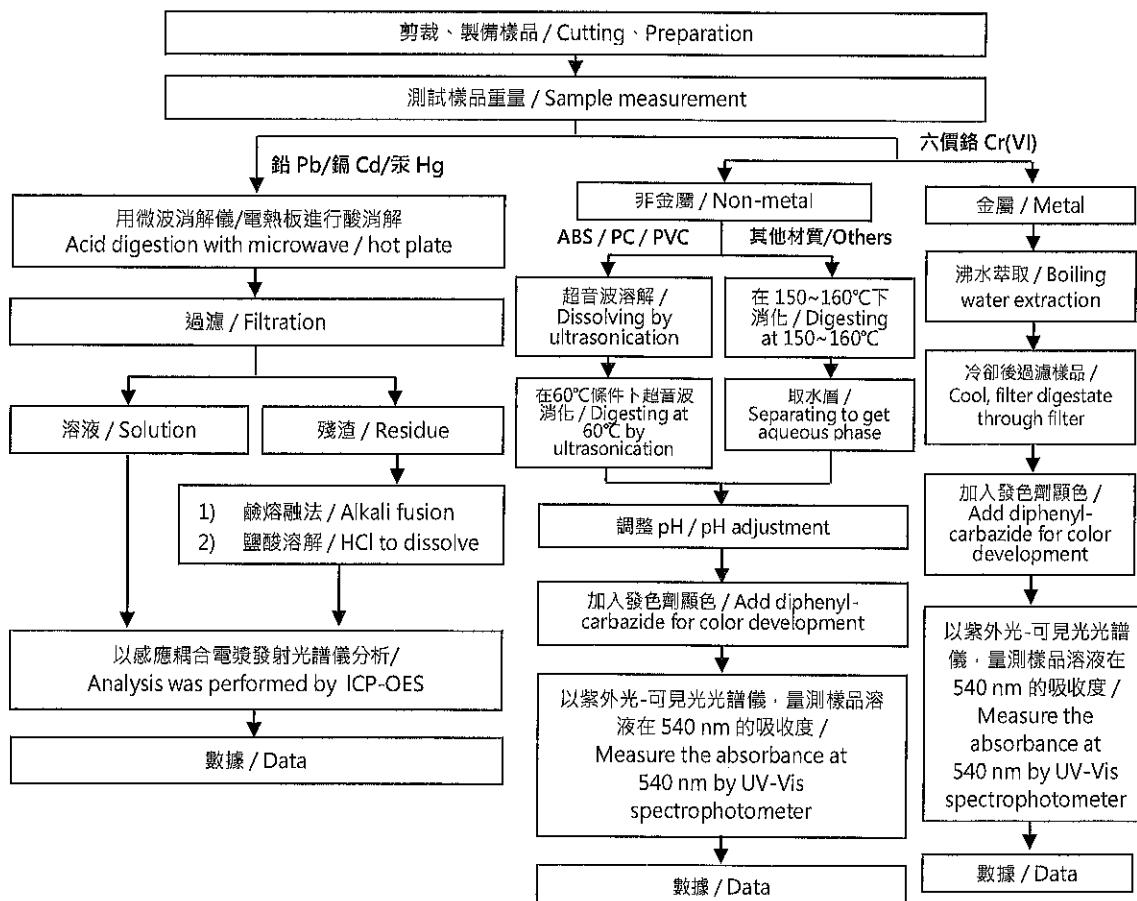
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重金屬流程圖 / Analytical flow chart of heavy metal

根據以下的流程圖之條件，樣品已完全溶解。(六價鉻測試方法除外)

These samples were dissolved totally by pre-conditioning method according to below flow chart.

(Cr⁶⁺ test method excluded)



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多溴聯苯/多溴聯苯醚分析流程圖 / Analytical flow chart - PBBs/PBDEs

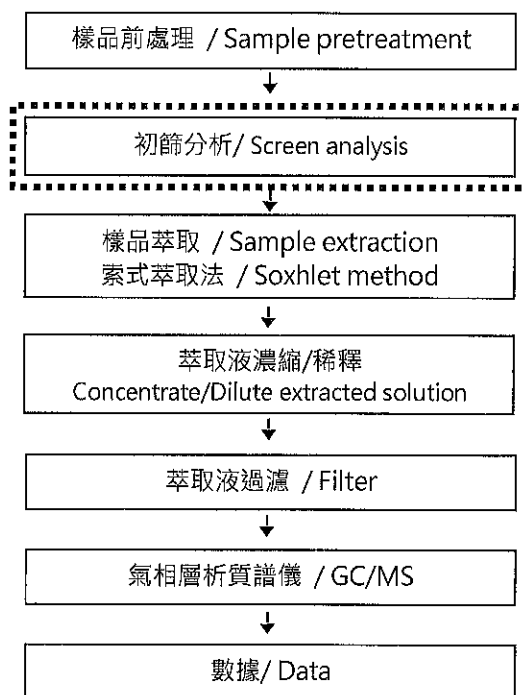
初次測試程序 / First testing process



選擇性篩檢程序 / Optional screen process



確認程序 / Confirmation process



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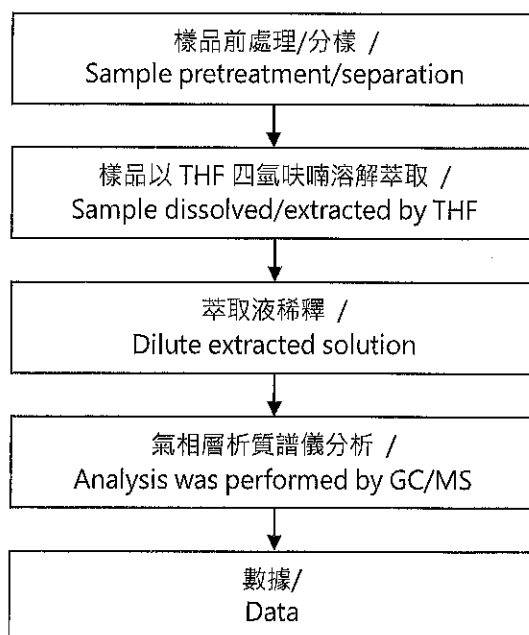
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可塑劑分析流程圖 / Analytical flow chart - Phthalate

【測試方法/Test method: IEC 62321-8】



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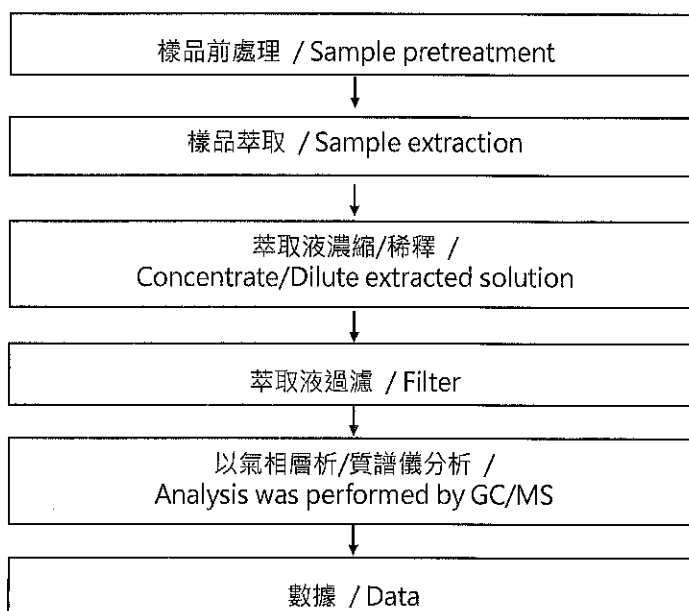
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六溴環十二烷分析流程圖 / Analytical flow chart - HBCDD



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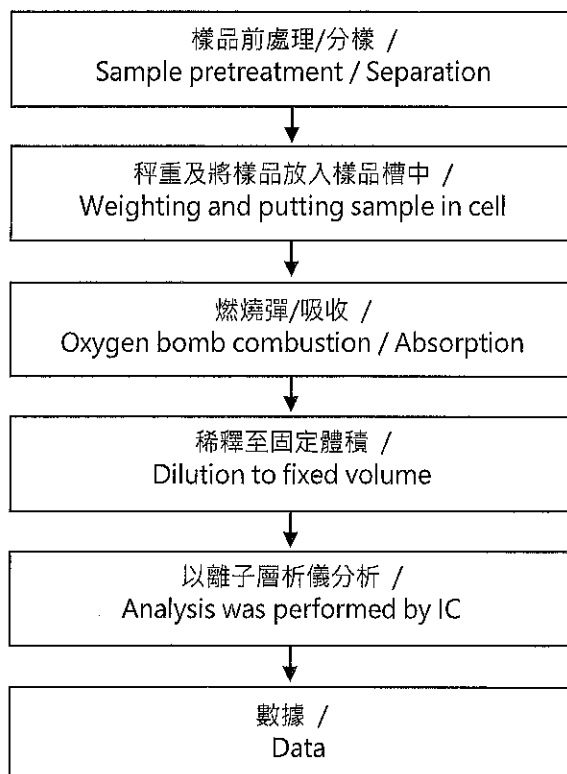
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中國·江蘇省·宿遷市·泗洪縣·經濟開發區杭州路南側·建設北路東側 (THE SOUTH HANGZHOU ROAD AND THE EAST JIANGSHE ROAD · ECONOMIC DEVELOPMENT ZONE · SIHONG COUNTY · SUQIANCITY · JIANGSU PROVINCE · P.R · CHINA)

臺北市信義區信義路5段5號3樓E06室 (ROOM E06, 3RD FLOOR, NO.5, SECTION 5, XINYI ROAD, XINYI DISTRICT, TAIPEI CITY, TAIWAN)

鹵素分析流程圖 / Analytical flow chart - Halogen



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測試報告

Test Report

號碼(No.): ETR25303011

日期(Date): 21-Mar-2025

頁數(Page): 11 of 11

西北臺慶科技股份有限公司 (TAI-TECH ADVANCED ELECTRONICS CO., LTD.)

臺慶精密電子(昆山)有限公司 (TAI-TECH ADVANCED ELECTRONICS (KUN-SHAN) CO., LTD.)

慶邦電子元器件(泗洪)有限公司 (TAIPAQ ELECTRONICS (SI-HONG) CO., LTD.)

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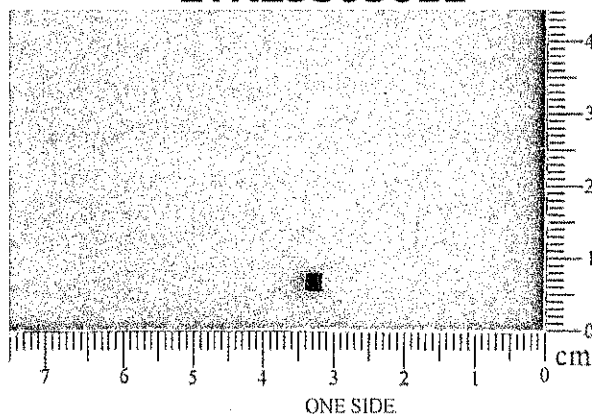
中國·江蘇省·宿遷市·泗洪縣·經濟開發區杭州路南側·建設北路東側 (THE SOUTH HANGZHOU ROAD AND THE EAST JIANGSU ROAD · ECONOMIC DEVELOPMENT ZONE · SIHONG COUNTY · SUQIANCITY · JIANGSU PROVINCE · P.R · CHINA)

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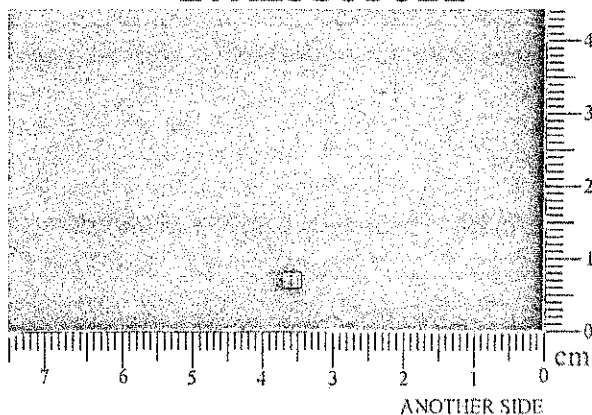
* 照片中如有箭頭標示，則表示為實際檢測之樣品/部位。*

(The tested sample / part is marked by an arrow if it's shown on the photo.)

ETR25303011



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** 報告結尾 (End of Report) **

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